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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Sheet	1	of	2

Application Number	10/061,459
Filing Date	1/31/02
First Named Inventor	Steven Teig, et al.
Group Art Unit	2171
Examiner Name	
Attorney Docket Number	SPLX.P0091

RELATED U.S. PATENT APPLICATIONS

Examiner* Initials	Cite No.[1]	U.S. Patent Application Serial Number		Name of Patentee or Applicant of Cited Document	Date of Filing MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
	1.	10/062,017		Steven Teig & Asmus Hetzel	01-31-02	
	2.	10/062,014		Steven Teig & Asmuz Hetzel	01-31-02	
	3.	10/062,044		Steven Teig & Asmus Hetzel	01-31-02	
	4.	10/066,264		Steven Teig & Asmuz Hetzel	01-31-02	
	5.	10/066,188		Steven Teig & Asmus Hetzel	01-31-02	
	6.	10/062,992		Steven Teig & Asmus Hetzel	01-31-02	
	7.	10/061,474		Steven Teig & Asmuz Hetzel	01-31-02	
	8.	10/061,719		Steven Teig & Asmus Hetzel	01-31-02	
	9.	10/066,456		Steven Teig & Asmus Hetzel	01-31-02	
	10.	10/062,993		Steven Teig & Asmus Hetzel	01-31-02	
	11.	10/062,047		Steven Teig & Asmuz Hetzel	01-31-02	

U.S. PATENT DOCUMENTS

Examiner* Initials	Cite No.[1]	U.S. Patent Document Number	Kind Code[2] (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
	12.	5,649,165		Jain et al.	07-15-97	
	13.	6,301,687	B1	Jain et al.	10-09-01	

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Sheet	2	of	2

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OTHER PRIOR ART – NON PATENT LITERATURE DOCUMENTS

Examiner* Initials	Cite No.[1]	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T[6]
	14.	D. Jongeneel, R. Otten, Y. Watanabe and R. K. Brayton, Area and Search Space Control for Technology Mapping, 37th Design Automation Conference, 86-91, 2000.	
	15.	Henrik Reif Andersen, An Introduction to Binary Decision Diagrams, October 1997 (minor revisions April 1998), 36 pp.	
	16.	Jerry Burch and David Long, Efficient Boolean Function Matching, Proc. ICCAD 1992, 408-411.	
	17.	John Fishburn, A Depth-Decreasing Heuristic for Combinational Logic; or How to Convert Ripple-Carry Adder into a Carry-Lookahead Adder or Anything In-Between, Proceedings of the 27th Design Automation Conference, 361-364, 1990.	
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	20.	Randal Bryant, Symbolic Boolean Manipulation with Ordered Binary Decision Diagrams, CMU CS Tech Report CMU-CS-92-160.	
	21.	Uwe Hinsberger and Reiner Kolla, Boolean Matching for Large Libraries, Proceedings of the 35th Design Automation Conference, 206-211, June 1998.	
	22.	Yuji Kukimoto, Robert K. Brayton, and Prashant Sawkar. Delay-Optimal Technology Mapping by DAG Covering, Dept. of Electrical Engineering and Computer Science, University of California, Berkeley, Strategic CAD Laboratories, Intel Corp., October 1997.	
	23.	Zbigniew J. Czech, et al., An Optimal Algorithm for Generating Minimal Perfect Hashing Functions, Information Processing Letters, 43(5); 257-264, October 1992	

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